

Application/Control No.	Applicant(s)/Patent under Reexamination
10/706,838 Examiner	CHANG ET AL. Art Unit
A. Dexter Tugbang	3729

	SEAR	CHED	
Class	Subclass	Date	Examiner
29	603.07 603.12 603.15 603.16	3/31/2006	ADT
	603.18		
	603.11		
	603.13		
	DIG 16		
360	320		
	324 324.1		
	324.11	V	V

INT	ERFERENCI	SEARC	HED
Class	Subclass	Date	Examiner

SEARCH NOT (INCLUDING SEARCH S	ES STRATEGY)
(11111111111111111111111111111111111111	DATE	EXMR
ext Search: NPL - IEEE Xplore atabase (see search history printout)	4/1/2006	ADT